

<b>Notice of References Cited</b>	Application/Control No. 10/776,720	Applicant(s)/Patent Under Reexamination SHIN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0004290	06-2001	Lee et al.	359/124
*	B	US-6,842,587	01-2005	McGhan et al.	398/201
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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